



Cu electrodeposition for the manufacturing of seamless SRF cavities

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- 1. Context / problematic
- 2. Technical proposal
- 3. Samples characterization
- 4. Toward a real cavity fabrication
- 5. Conclusion / perspectives







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Nb/Cu Cavities - Background



COST

Thermal Stability

<u>Manufacturing</u>: Cu OFE (10euros/kg) vs Nb RRR300 (800euros/kg)

<u>Operational</u>: Operation @ 4.2 K / Simpler cryostat (stainless steel vs Titanium) Cu substrate ensures SC film stabilization wrt thermo-magnetic breakdown



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What about the performances?



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Nb/Cu should compete with bulk Nb cavities → High Q → High Gradient





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Nb/Cu Cavities - Forming

Standard Route





Nb/Cu Cavities - Forming

Standard Route



Seamless Route





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Mandrel footprint



















Shape tolerance requirement in seamless process by spinning need strong R&D effort. On-going in INFN-LNL.





Shape tolerance requirement in seamless process by spinning need strong R&D effort. On-going in INFN-LNL (see Cristian Pira's talk).

Could we manufacture a seamless cavity with a controlled surface state and "machine grade" tolerances ?







Cu electroforming - proposal

Small diameter UHV chambers

Mandrel preparation	Thin film sputtering	Chamber electroforming	Mandrel removal			
				TID: 3mm, OD: 5mm		
\bigcirc	\bigcirc					
Al mandrel	NEG and Cu coatings	Copper electroforming	Al removal	Successfully developed at CERN [3] for CLIC and new generation light sources.		



Cu electroforming - proposal

Small diameter UHV chambers





Toward SRF cavities substrates ?





2.

[3]: Journal of Vacuum Science & Technology A 36, 021601 (2018); doi: 10.1116/1.4999539 G. Rosaz et al. SRF2019

Cu electroforming - Principle





Cu electroforming - Principle



Electrodeposition of Cu, 2 A/dm², 96 hours, copper sulphate-sulphuric acid bath

- 2-3 mm of Cu deposited (desired chamber wall thickness)
- Two plating procedures: DC plating with brightener and pulse plating without additives







Cu electroforming - approach



Samples









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Mechanical Properties

Microstructure





Mechanical Properties

Microstructure

3.



Hardness/Young modulus / UTS





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Cryogenic Properties



- RRR easily matches Cu OFE specs after thermal treatment



Cryogenic Properties



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- PP can lead to very high RRR



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Residual Resistive Ratio - thermal



- More to come to study thermal treatment effects





Surface quality

	Roughness				
	Standard mai	Standard mandrel machining		Diamond mandrel machining	
μm	DC plating	Pulse plating	DC plating	Pulse Plating	
Al-R _a	(0.49		0.002	



Roughness

	Standard man	drel machining	Diamond mandrel machining		
μm	DC plating	Pulse plating	DC plating	Pulse Plating	
Al-R _a	0.	49	0.002		
Cu-R _a	0.15 / 0.43	0.64 / 0.66			







Roughness Standard mandrel machining **Diamond mandrel machining DC** plating **Pulse plating DC** plating **Pulse Plating** μm 0.49 0.002 Al-R_a Cu-R_a 0.15 / 0.43 0.64 / 0.66 0.030 / 0.017 0.030 / 0.027 3.00 3.00 2.00 2.00 1.00 1.00 0.00 -2.00 -20 -40 -50 -2.00 - -3.00 -2.00



Roughness **Standard mandrel machining Diamond mandrel machining DC** plating **Pulse plating DC** plating **Pulse Plating** μm Al-R_a 0.49 0.002 Cu-R₂ 0.15 / 0.43 0.64 / 0.66 0.030 / 0.017 0.030 / 0.027 1.00 0.00 -2.00

Surface quality can be easily controlled with the mandrel surface finish





Plated copper as good as OFE grade bulk

Mechanical properties Cryogenic properties Surface quality



Let's try to make a cavity







Dummy mandrels

4.



Old 1.5 GHz Al cavity recycling

For thickness profile evaluation and feasibility test



Dummy mandrels

4.



cavity recycling

For thickness profile evaluation and feasibility test



For electroforming optimization on low-cost substrate

Test mandrels (Al tubes welded on convex tanks)



Dummy mandrels



For thickness profile evaluation and feasibility test



For electroforming optimization on low-cost substrate

Old 1.5 GHz Al cavity recycling

Test mandrels (Al tubes welded on convex tanks)

First tests





Dummy mandrels



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Thickness Profile

Sampling



Cut-out of the cavity

Iris thickness 2 to 3 times smaller than equator - Anticipated \rightarrow to be optimized later on

Hardness constant over the profile: DC: 114 HV0.1 PP: 55 HV0.1



1st Demonstrator

4.



Dummy cavity in PVD chamber





















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Conclusion / Perspectives

- Electroformed copper has been extensively characterized
 - RRR up to 2000 upon thermal treatment
 - Roughness controlled by mandrel surface state
 - Mechanical properties comparable to OFE-Cu or annealed OFE-Cu
 - Chemical composition : OFE grade (not shown here)
- Flanges assembly demonstrated

Next steps:

- Real 1.3 GHz cavity to be manufactured Fully turned mandrel available
- Nb thin film coating using best recipe and RF testing
- Investigate thin film behaviour depending on substrate properties (roughness, purity...)
- Thickness profile optimization
- Cost study



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